

QT-Brightek Optocoupler Series

5-PIN 1 Mbit/s High Speed Transistor Coupler

Part No.: QTM452, 453

Product: QTM452_453	Date: February 12, 2018	Page 1 of 15
	Version# 1.0	

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Introduction

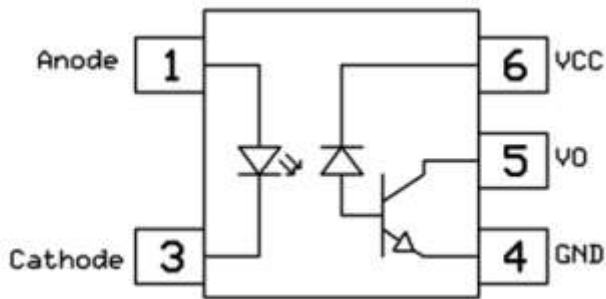
Feature:

- High Speed 1Mbit/s
- High Isolation voltage between input and output (Viso = 3750V rms)
- Guaranteed CTR performance from 0 °C to 70 °C
- Mini-Flat package

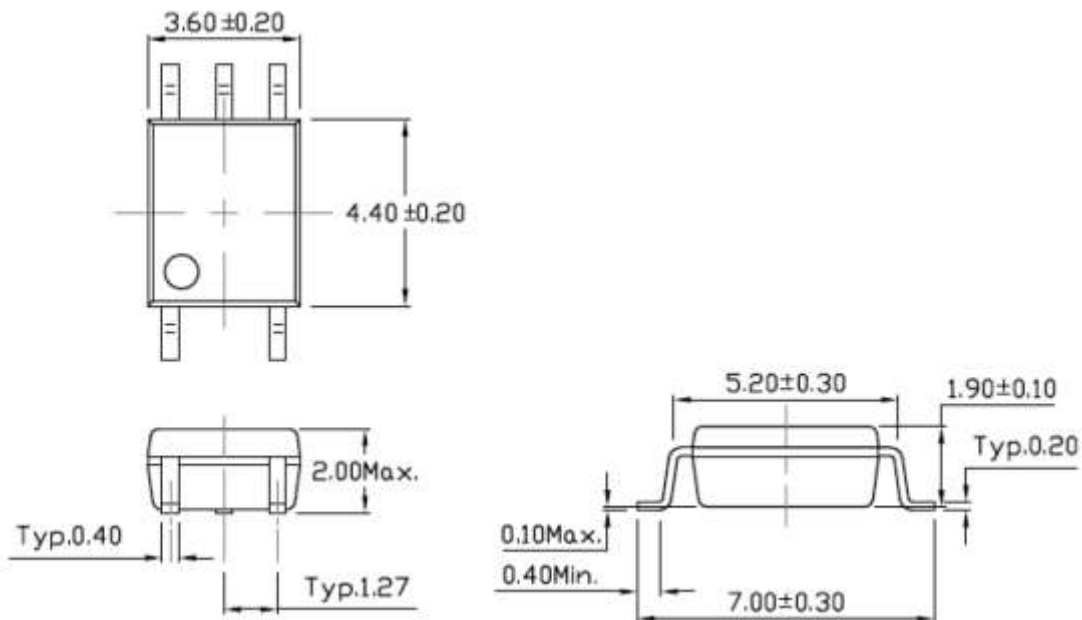
Certification & Compliance:

- Pb free and RoHS Compliant
- UL recognized (File #E338132)
- cUL recognized (File #E338132)
- VDE (Pending Approval)

Schematic:



Dimension: (Dot location indicates pin 1)



All Dimensions are in mm

Absolute Maximum Rating

Symbol	Parameter	Rating	Units
V _{ISO}	Isolation Voltage	3750	V _{RMS}
T _{STG}	Storage Temperature	-55 ~ +125	°C
T _{OPR}	Operating Temperature	-55 ~ +100	°C
T _{SOL}	Lead Solder Temperature	260 for 10 sec	°C
EMITTER			
I _F	Continuous Forward Current	25	mA
I _{FP}	Peak Forward Current (50% duty, 1ms P.W)	50	mA
I _{FP(TRANS)}	Peak transient Current (≤ 1us P.W, 300pps)	1	A
V _R	Reverse Voltage	5	V
P _D	Power Dissipation	45	mW
	Power Dissipation Derated above 100°C	-	mW/°C
DETECTOR			
P _D	Power Dissipation	100	mW
I _{O(AVG)}	Average Output current	8	mA
I _{O(Peak)}	Peak Output current	16	mA
V _O	Output voltage	-0.5 to 20	V
V _{CC}	Supply voltage	-0.5 to 30	V

Electrical Characteristic (T_A=25 °C)

Emitter

Symbol	Characteristics	Device	Test Condition	Range			Unit
				Min	Typ	Max	
V _F	Forward Voltage	-	I _F = 16mA	-	1.45	1.6	V
V _R	Reverse Voltage		I _R = 10μA	5	-	-	V
ΔV _F /ΔT _A	Temperature coefficient of forward voltage		I _F = 16mA	-	-1.6	-	mV/°C

Detector

Symbol	Characteristic	Device	Test Condition	Range			Unit
				Min	Typ	Max	
I _{OH}	Logic High Output Current	-	I _F =0mA, V _O =V _{CC} =5.5V, T _A =25°C	-	0.001	0.5	μA
			I _F =0mA, V _O =V _{CC} =15V, T _A =25°C	-	0.01	1	
			I _F =0mA, V _O =V _{CC} =15V	-	-	50	
I _{CCL}	Logic Low Supply Current	-	I _F =16mA, V _O =Open, V _{CC} =15V	-	120	200	μA
I _{CCH}	Logic High Supply Current	-	I _F =0mA, V _O =Open, V _{CC} =15V, T _A =25°C	-	0.01	1	μA
			I _F =0mA, V _O =Open, V _{CC} =15V	-	-	2	

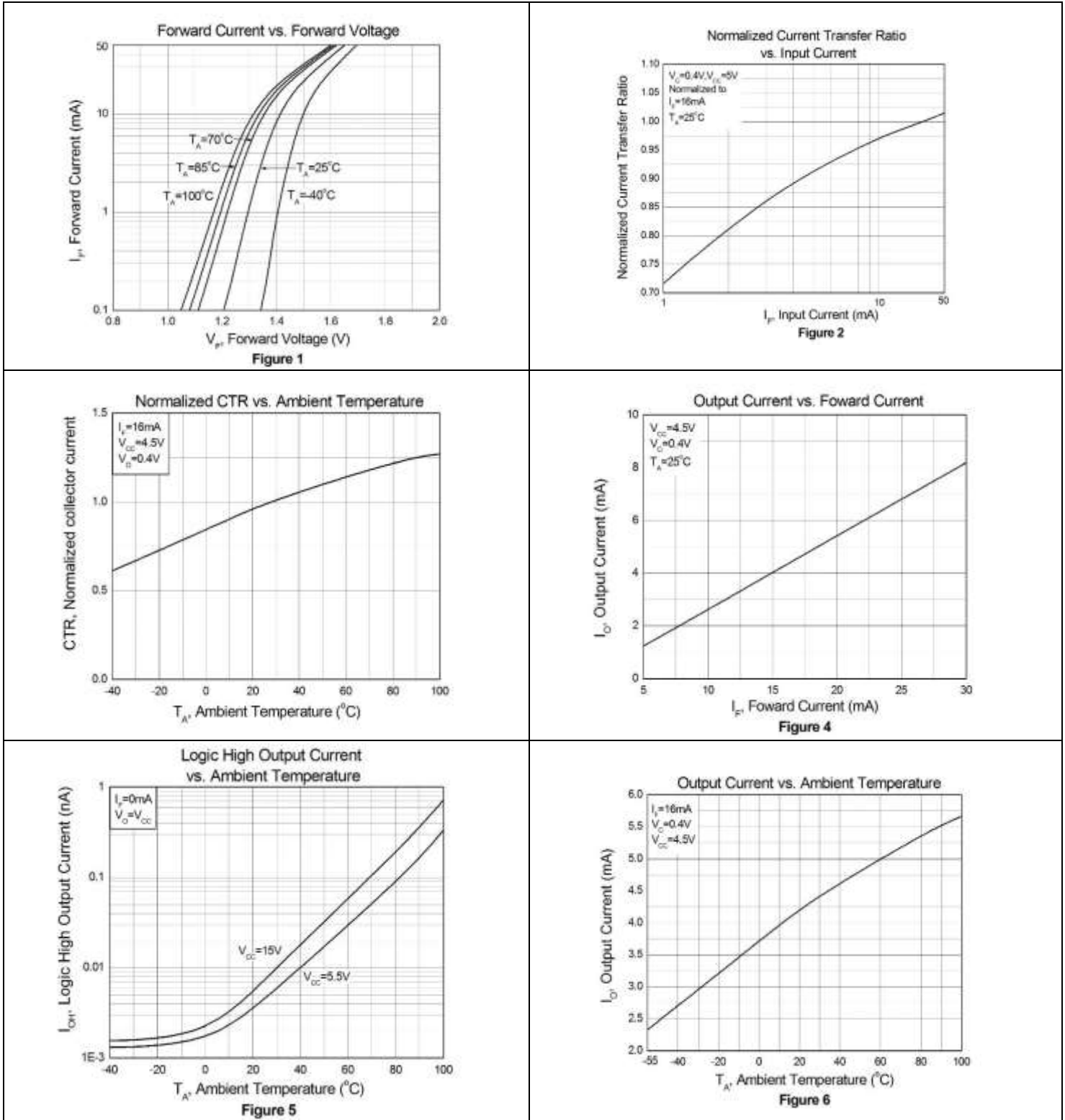
Transfer Characteristics (T_A=0 to 70C unless specified otherwise)

Symbol	Characteristic	Device	Test Condition	Range			Unit
				Min	Typ	Max	
CTR	Current Transfer Ratio		I _F =16mA, V _O =0.4V, V _{CC} =4.5V, T _A =25°C	20	-	50	%
			I _F =16mA, V _O =0.5V, V _{CC} =4.5V	15	-	-	
V _{OL}	Logic Low Output Voltage		I _F =16mA, I _O =3mA, V _{CC} =4.5V, T _A =25°C	-	-	0.4	V
			I _F =16mA, I _O =2.4mA, V _{CC} =4.5V	-	-	0.5	Ω

Switching Characteristics (TA=25°C, Vcc=5V)

Symbol	Characteristic	Device	Test Condition	Range			Unit
				Min	Typ	Max	
T _{PHL}	Propagation Delay Time Logic High to Logic Low		I _F =16mA, R _L =1.9KΩ, T _A =25°C	-	0.3 5	0.8	μs
			I _F =16mA, R _L =1.9KΩ	-	-	1.0	
T _{PLH}	Propagation Delay Time Logic Low to Logic High		I _F =16mA, R _L =1.9KΩ, T _A =25°C	-	0.3	0.8	μs
			I _F =16mA, R _L =1.9KΩ	-	-	1.0	
CM _H	Common Mode Transient Immunity at Logic High	CTM452	I _F = 0mA, V _{CM} =10Vp-p, R _L =1.9KΩ, T _A =25°C	5000	-	-	V/μs
		CTM453	I _F = 0mA, V _{CM} =1500Vp-p, R _L =1.9KΩ, T _A =25°C	15000	-		
CM _L	Common Mode Transient Immunity at Logic Low	CTM452	I _F = 0mA, V _{CM} =10Vp-p, R _L =1.9KΩ, T _A =25°C	5000	-	-	V/μs
		CTM453	I _F = 0mA, V _{CM} =1500Vp-p, R _L =1.9KΩ, T _A =25°C	15000	-		

Characteristic Curves



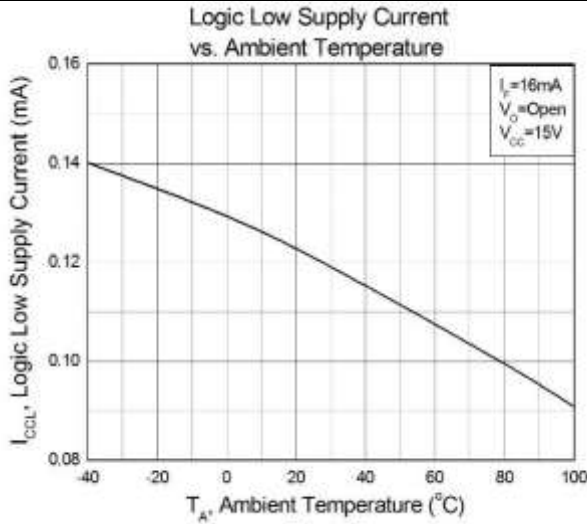


Figure 7

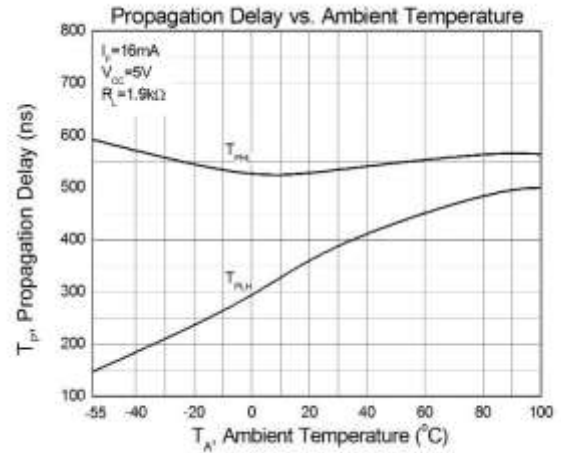


Figure 8

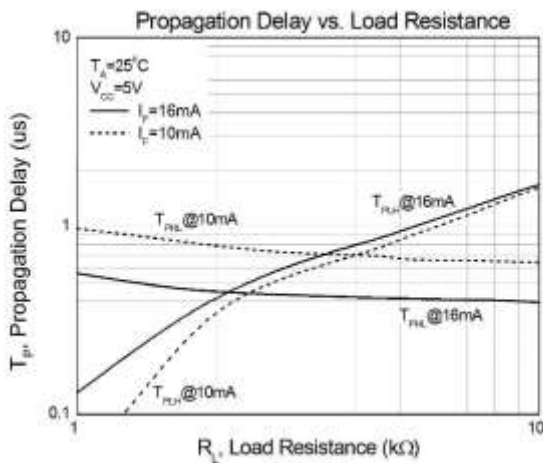


Figure 9

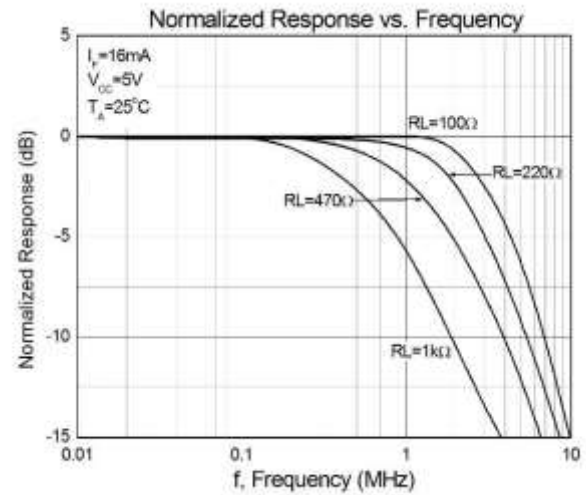
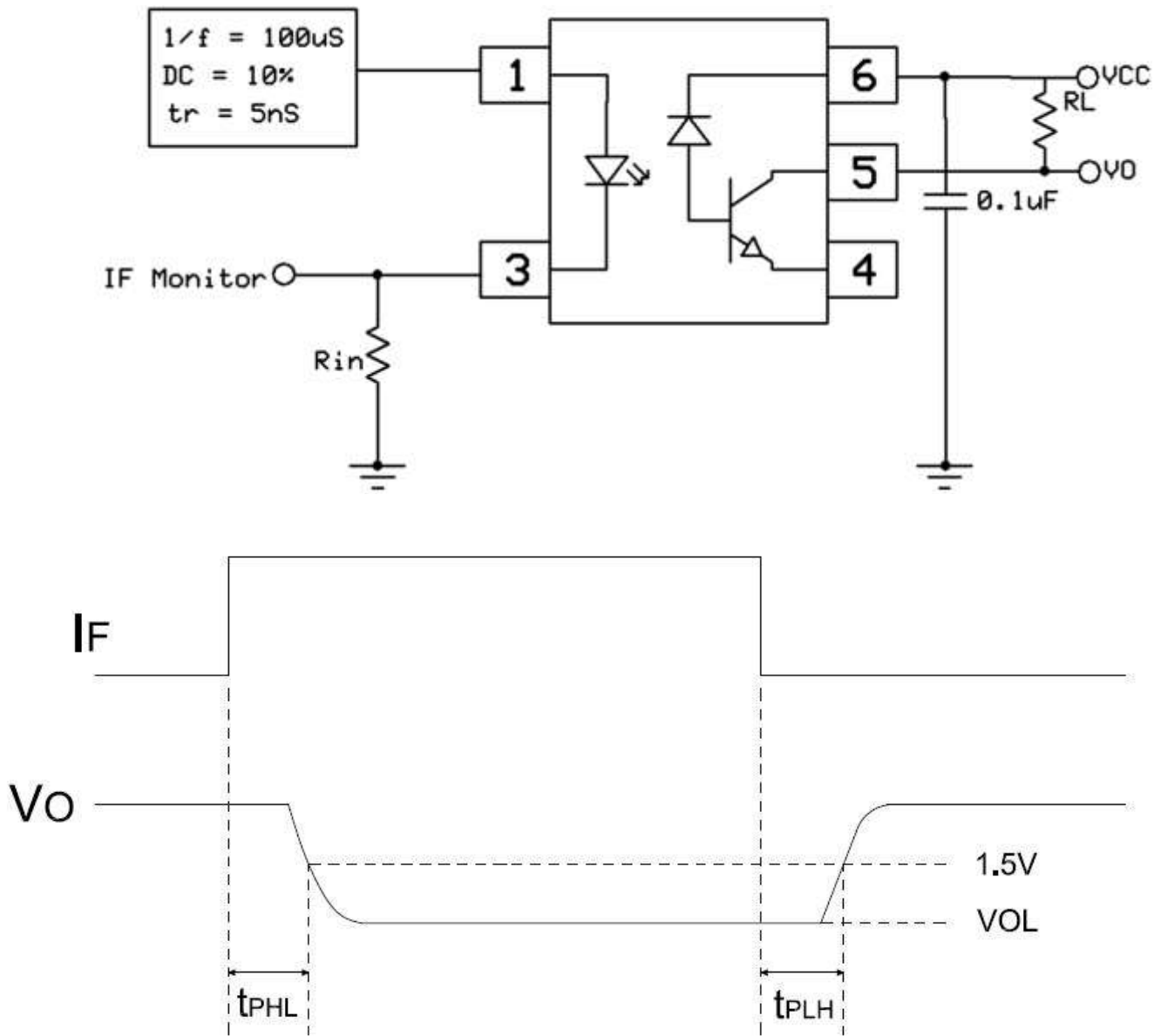
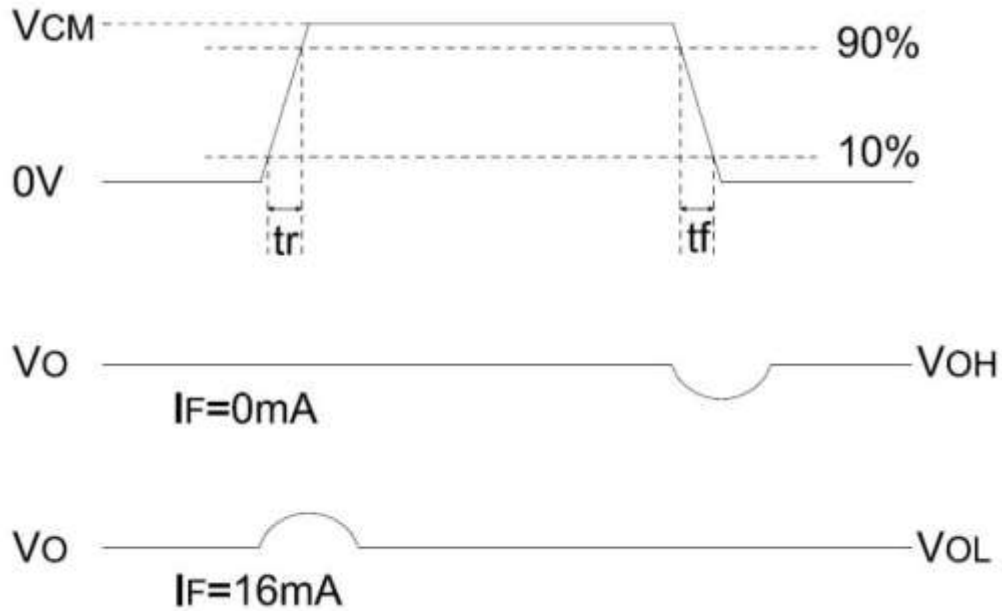
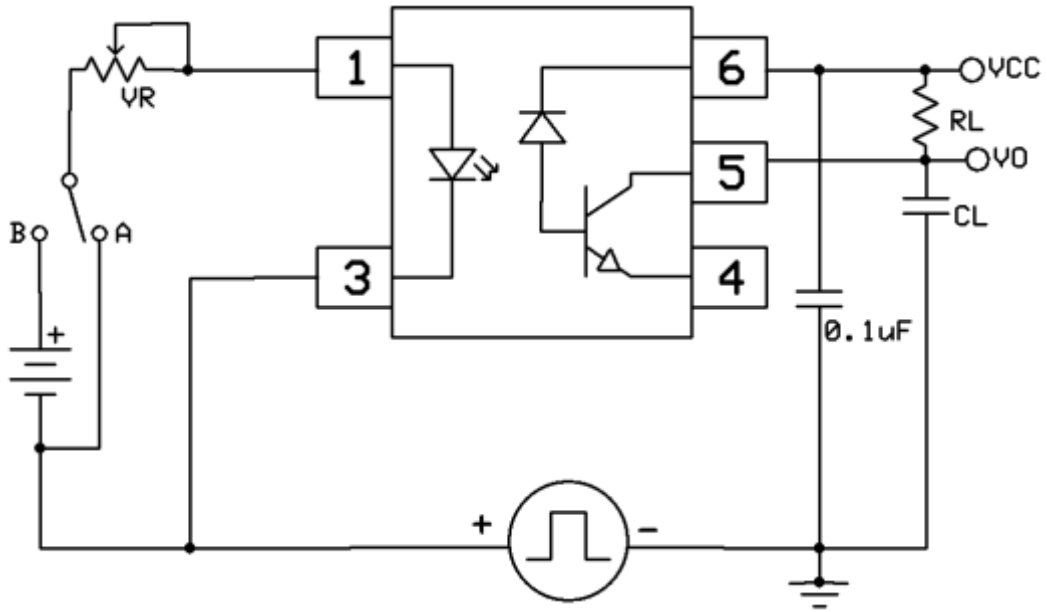


Figure 10

Test Circuits

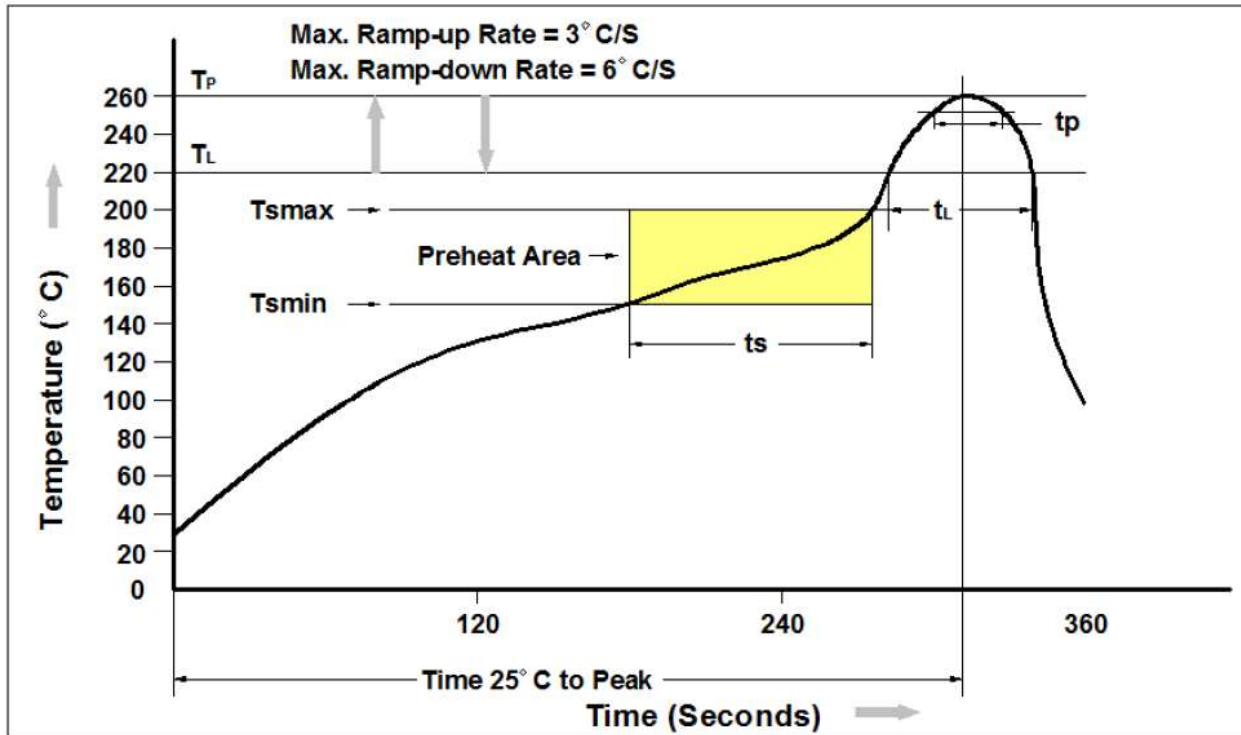


Switching Time Test Circuit



CMR Test Circuit

Solder Profile & Footprint

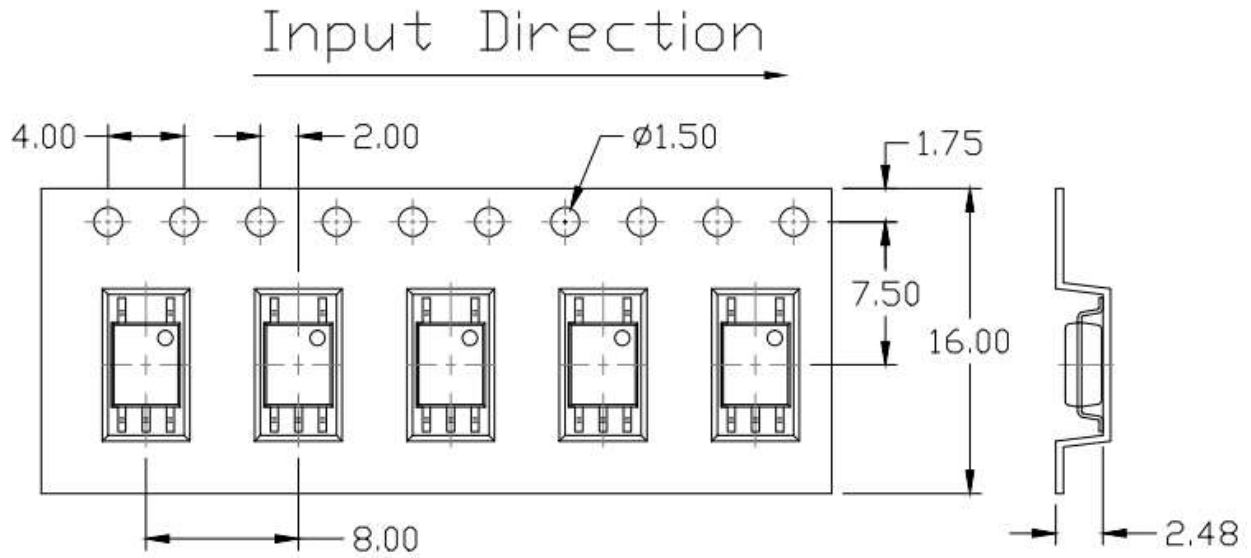


Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150°C
Temperature Max. (T _{smax})	200°C
Time (t _s) from (T _{smin} to T _{smax})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.

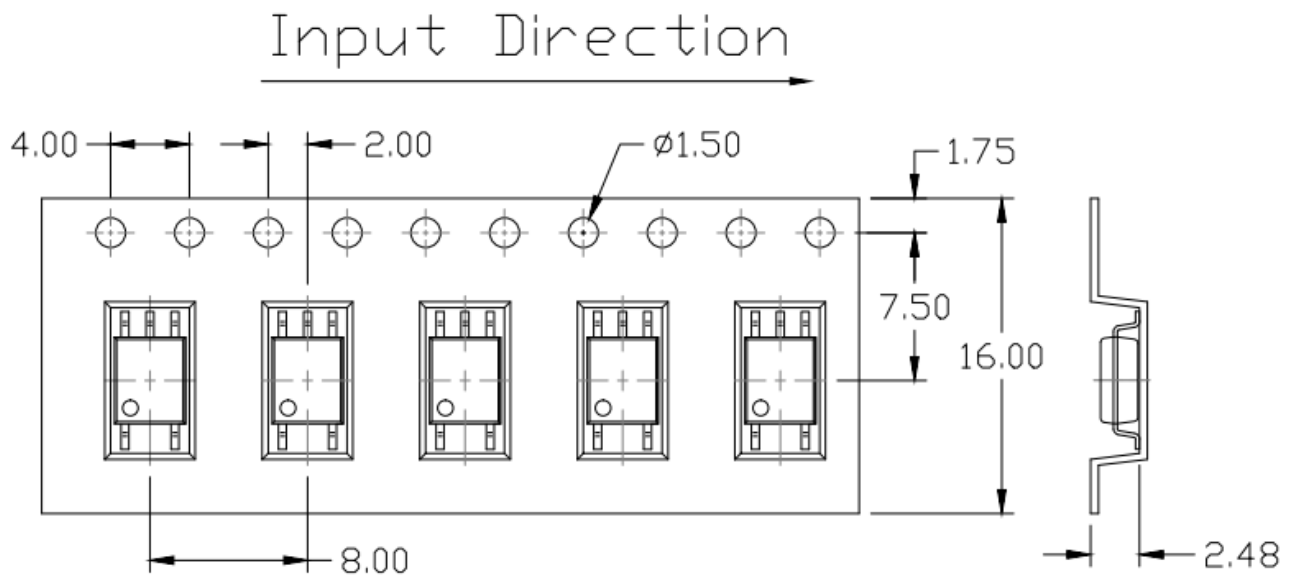
Packing & Labeling

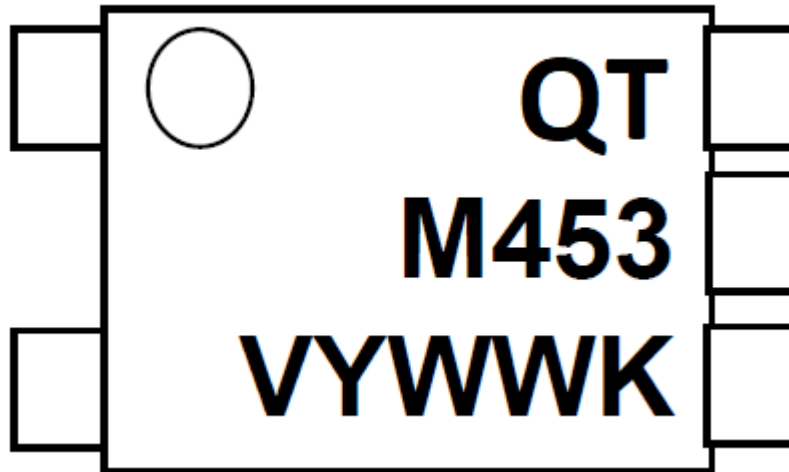
Tape Dimension:

Option T1



Option T2



Device Marking

QT = QT-Brightek Corporation
 M= Mini-Flat Package
 453 = part number
 Y = Year
 WW = Week
 V = VDE Option
 K= Manufacturing code

Ordering Information

QTM45X(V)(Z)
 X = Part number (X=2 or 3)
 V = VDE option (V or None)
 Z = Tape and reel option (T1 or T2)

Option	Description	Quantity
T1	Surface Mount Lead Forming – with Option 1 Taping	3000 pcs/ reel
T2	Surface Mount Lead Forming – with Option 2 Taping	3000 pcs/ reel



Revision History

Description:	Revision #	Revision Date
Initial release of QTM452_453	1.0	02/12/2018

Disclaimer

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